

**Search Notes**

Application/Control No.

10/840,222

Examiner

EDMUND H. LEE

Applicant(s)/Patent under  
Reexamination

IWAMI ET AL.

Art Unit

1732

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
264	248,250	12/29/2006	EHL
	279.1,325		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
UPDATED EAST	12/29/2006	EHL
UPDATED CLASS/SUBCLASS SEARCH...264/248,250,279.1,325		